

Notice of References Cited

Application/Control No.

10/567,584

Applicant(s)/Patent Under

Reexamination

YAMAMICHI ET AL.

Examiner

MICHAEL R. VAUGHAN

Art Unit

2431

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0042777 A1	04-2002	Yoshida et al.	705/41
*	B US-6,434,535 B1	08-2002	Kupka et al.	705/24
*	C US-2003/0018586 A1	01-2003	Krahn, Gerald C.	705/58
*	D US-2003/0031319 A1	02-2003	Abe et al.	380/232
*	E US-2003/0200216 A1	10-2003	Hayes et al.	707/9
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2003132425 A	05-2003	Japan	OTSUKA et al.	G07F 17/00
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.